TOSHIBA Insulated Gate Bipolar Transistor Silicon N Channel IGBT

# GT40T301

#### Parallel Resonance Inverter Switching Applications

Unit: mm

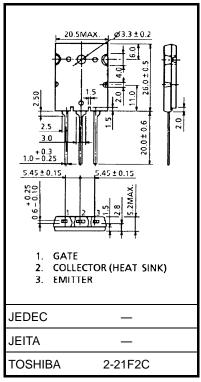
- FRD included between emitter and collector
- Enhancement mode type
- High speed IGBT :  $t_f = 0.25 \mu s$  (typ.) (I<sub>C</sub> = 40 A)

FRD :  $t_{rr} = 0.7 \mu s$  (typ.) (di/dt = -20 A/ $\mu s$ )

• Low saturation voltage:  $V_{CE (sat)} = 3.7 \text{ V (typ.)}$  ( $I_{C} = 40 \text{ A}$ )

#### **Absolute Maximum Ratings (Ta = 25°C)**

Characteristics		Symbol	Rating	Unit	
Collector-emitter voltage		V <sub>CES</sub>	1500	V	
Gate-emitter voltage		V <sub>GES</sub>	±25	V	
Collector current	DC	Ic	40	А	
	1 ms	I <sub>CP</sub>	80		
Emitter-collector forward current	DC	I <sub>ECF</sub>	30	А	
	1 ms	I <sub>ECPF</sub>	80	ζ	
Collector power dissipation (Tc = 25°C)		PC	200	W	
Junction temperature		Tj	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	

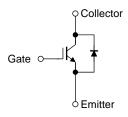


Weight: 9.75 g (typ.)

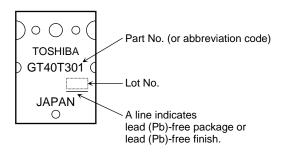
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

## **Equivalent Circuit**



### Marking



# **Electrical Characteristics (Ta = 25°C)**

Characteristics		Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GES</sub>	$V_{GE} = \pm 25 \text{ V}, V_{CE} = 0$	_	_	±500	nA
Collector cut-off current		I <sub>CES</sub>	V <sub>CE</sub> = 1500 V, V <sub>GE</sub> = 0	_	_	1.0	mA
Gate-emitter cut-off voltage		V <sub>GE</sub> (OFF)	I <sub>C</sub> = 40 mA, V <sub>CE</sub> = 5 V	4.0	_	7.0	V
Collector-emitter	Collector-emitter saturation voltage V <sub>CE</sub> (sat) I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V		I <sub>C</sub> = 40 A, V <sub>GE</sub> = 15 V	_	3.7	5.0	V
Input capacitance		C <sub>ies</sub>	V <sub>CE</sub> = 10 V, V <sub>GE</sub> = 0, f = 1 MHz	_	2900	_	pF
Switching time  Tu	Rise time	t <sub>r</sub>		_	0.40	_	μs
	Turn-on time	t <sub>on</sub>	51 Ω	_	0.45	_	
	Fall time	t <sub>f</sub>	15 V 51 Ω C C C C C C C C C C C C C C C C C C		0.23	0.40	
	Turn-off time	t <sub>off</sub>		_	0.6	_	
Emitter-collector forward voltage		V <sub>ECF</sub>	I <sub>ECF</sub> = 30 A, V <sub>GE</sub> = 0	_	1.9	2.5	V
Reverse recovery time		t <sub>rr</sub>	$I_{ECF} = 30 \text{ A}, V_{GE} = 0, di/dt = -20 \text{ A}/\mu\text{s}$	_	0.7	3.0	μS
Thermal resistance		R <sub>th (j-c)</sub>	IGBT	_	_	0.625	°C/W
			Diode			1.25	

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